# Measurement of charged particle spectra emitted following muon nuclear capture in Si nuclei S. Kawase<sup>1</sup>, K. Kitafuji<sup>1</sup>, T. Kawata<sup>1</sup>, Y. Watanabe<sup>1</sup>, F. Minato<sup>1</sup>, M. Niikura<sup>2</sup>, R. Mizuno<sup>3</sup>, D. Tomono<sup>4,5</sup>, K. Ishida<sup>2,5</sup>, A.D. Hillier<sup>6</sup> <sup>1</sup>Kyushu U, <sup>2</sup>RIKEN, <sup>3</sup>U Tokyo, <sup>4</sup>Osaka U, <sup>5</sup>KEK, <sup>6</sup>STFC UKRI

#### Muon induced soft error

When radiation enters a semiconductor device, soft errors can occur. The impact of cosmic-ray muons is expected to increase with the miniaturization of semiconductor processes.

B. D. Sierawski et al, IEEE Trans. Nucl. Sci. 57, 3273 (2010)

Secondary charged particles emitted following the (negative) muon nuclear capture in Si, increase the soft-error cross section.



#### Particle identification

Particles stop in 500um Si: Pulse shape analysis (PSA) method w/ nTD-Si S. Kawase et al., Nucl. Instrum. Meth. Phys. Res. A 1059, 168984 (2024).



Particles penetrate 325 or 500 µm Si: Conventional  $\Delta E$ -E method using Si ( $\Delta E$ ) and CsI(TI) (E)



W. Liao et al., IEEE Trans. Nucl. Sci., 65 (8), 1734 (2018).

Energy spectra of charged particles emitted after muon nuclear capture in Si is crucial for the evaluation of cosmic-ray-muon-induced soft-error rate for advanced semiconductor devices.

## Muon nuclear capture (µNC)



## Measured energy spectra

 Measured energy spectra for p, d, t, and  $\alpha$  were obtained for over a wider energy range than preceding measurements

- Energy loss in the Si target is not considered here and the initial energy spectra in the low energy region may increase slightly
- The theoretical model calc. reproduce the overall shape.

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Rev. C 105, 035501 (2022), Yu. G. Budyashov et al., Sov. Phys. 33, 11-15 (1971)

## Experiment @ RIKEN-RAL

The experiment was conducted at the RIKEN-RAL muon facility at the Rutherford Appleton Laboratory, England.

RIKEN-RAL: A. D. Hillier et al., Phil. Trans. R. Soc. A 377, 20180064 (2019).

Slow negative muon beam (18.5 and 21.5 MeV/c for 25 and 200 µm targets) was

The ratio of contributions Ш 10<sup>-5</sup> from preequilibrium and tritor compound processes may be slightly different from calc. 10<sup>-6</sup> 10 20 30 50 40 Energy (MeV)

### Unfolding analysis

- Emitted charged particles lose their energy in the target
  - It may affect the height and shape of evaporation peak
- To compensate the energy loss in the target, unfolding analysis was carried out using an unfolding framework RooUnfold. RooUnfold: L. Brenner et al., Int. J. Mod. Phys. A 35, 2050145 (2020).
- Detectors' response functions were prepared with a Monte Carlo simulation using Geant4. Geant4: J. Allison et al., Nucl. Instrum. Meth. Phys. Res. A 835, 1 (2016).
- Analysis for d, t,  $\alpha$  and the detailed evaluation of uncertainties are in progress ....



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stopped in a thin Si target to induce µNC. The particle identification and energy measurement of emitted charged particles were performed.





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#### Summary and Outlook

- Energy spectra of charged particles emitted after µNC are crucial in the evaluation of muon-induced soft error rate in semiconductor devices.
- Energy spectra of emitted particles reflect various processes in  $\mu NC$ , including the formation of compound nuclei.
- Energy spectra of light nuclear fragments emitted following µNC in <sup>nat</sup>Si were measured in the RIKEN-RAL muon facility.
- We are planning similar measurements of  $\mu NC$  in heavier nuclei such as <u>Co, Ni, and Cu</u> for comprehensive understanding of the  $\mu$ NC process. • Data across a magic number would be helpful to understand the process.

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